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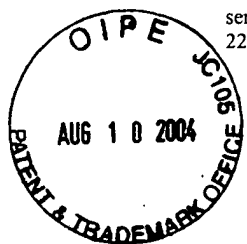
I hereby certify that this correspondence is being deposited with the United States Postal Services "Express Mail Post Office to Addressee" service under 37 CFR § 1.10 on the date indicated above and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

By: Veronica Weinstein
Veronica Weinstein

PATENT

Customer No. 22,852

Attorney Docket No. 9140.0014



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)
)
Demaray, et al.) Group Art Unit: 1731
)
Serial No.: 09/903,081) Examiner: John M. Hoffmann
)
Filed: July 10, 2001) Confirmation No. 1225
)
For: AS-DEPOSITED PLANAR OPTICAL)
WAVEGUIDES WITH LOW)
SCATTERING LOSS AND)
METHODS FOR THEIR)
MANUFACTURE)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(c)

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(c), Applicants bring to the attention of the Examiner the documents listed on the attached PTO 1449. This Information Disclosure Statement is being filed after the events recited in Section 1.97(b) but, to the undersigned's knowledge, before the mailing date of either a Final action, Quayle action, or a Notice of Allowance. Under the provisions of 37 C.F.R. § 1.97(c), this Information Disclosure Statement

is accompanied by a fee of \$180.00 as specified by Section 1.17(p). The Commissioner is hereby authorized to charge this fee to our Deposit Account No. 06-0916.

Several references were submitted with Information Disclosure Statement of July 10, 2001, and not considered by the Examiner. Applicants resubmit the Hubner et al, Lee et al, Marquez et al, Ohkubo et al, and Ono et al. references, providing requested information regarding the date of publication of these references as requested by the Examiner.

Copies of the listed documents are attached.

With regard to the Examiner's objection to Schermer et al. reference, Applicants are unable to provide a better copy of the Schermer et al. reference. The copy submitted herewith is the best copy available to the Applicants. Applicants respectfully request that the Examiner consider this reference as provided.

Applicants respectfully request that the Examiner consider the listed documents and indicate that they were considered by making appropriate notations on the attached form.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that each or all of the listed documents are material or constitute "prior art." If the Examiner applies any of the documents as prior art against any claims in the application and Applicants determine that the cited documents do not constitute "prior art" under United States law, Applicants reserve the right to present to the office the relevant facts and law regarding the appropriate status of such documents.

Applicants further reserve the right to take appropriate action to establish the patentability of the disclosed invention over the listed documents, should one or more of the documents be applied against the claims of the present application.

If there is any additional fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW,
GARRETT & DUNNER, L.L.P.

Dated: August 10, 2004

By:  _____

Gary J. Edwards

Reg. No. 41,008

INFORMATION DISCLOSURE CITATION

Atty. Docket No.	09140-0014-00000	Appln. No.	09/903,081
Applicant	Demaray et al.		
Filing Date	July 10, 2001	Group:	1731



U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Issue/ Publication Date	Name	Class	Sub Class	Filing Date If Appropriate
	2001/0027159	Oct. 04, 2001	Kaneyoshi	501	152	
	2002/0106297	Aug. 08, 2002	Ueno et al.	419	12	
	2003/0019326	Jan. 30, 2003	Han et al.	45	245	
	2003/0063883	Apr. 3, 2003	Demaray et al.	385	129	
	2003/0175142	Sep. 18, 2003	Milonopoulou et al.	419	49	
	4,437,966	Mar. 7, 1961	Hope et al	204	298	
	4,915,810	Apr. 10, 1990	Kestigian et al.	204	298.04	
	4,978,437	Dec. 18, 1990	Wirz	204	192.	
	5,085,904	Feb. 4, 1992	Deak et al.	428	35.7	
	5,107,538	Apr. 21, 1992	Benton et al.	385	130	
	5,119,460	Jun. 2, 1992	Bruce et al.	385	142	
	5,174,876	Dec. 29, 1992	Buchal et al.	427	526	
	5,200,029	Apr. 6, 1993	Bruce et al.	156	657	
	5,206,925	Apr. 27, 1993	Nakazawa et al.	385	142	
	5,237,439	Aug. 17, 1993	Misono et al.	359	74	
	5,225,288	Jul. 6, 1993	Beeson et al.	428	475.5	
	5,252,194	Oct. 12, 1993	Demaray et al.	204	298	
	5,303,319	Apr. 12, 1994	Ford et al.	385	131	
	5,381,262	Jan. 10, 1995	Arima et al.	359	341	
	5,427,669	Jun. 27, 1995	Drummond	204	298.2	

Examiner	Date Considered
<p>*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	
Form PTO 1449	Patent and Trademark Office - U.S. Department of Commerce

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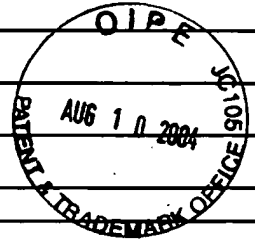
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Examiner Initial*		Document Number	Issue/ Publication Date	Name	Class	Sub Class	Filing Date If Appropriate
		5,457,569	Oct. 10, 1995	Liou et al.	359	344	
		5,475,528	Dec. 12, 1995	LaBorde	359	341	
		5,483,613	Jan. 9, 1996	Bruce et al.	385	129	
		5,555,127	Sep. 10, 1996	Abdelkader et al.	359	341	
		5,563,979	Oct. 8, 1996	Bruce et al.	385	142	
		5,565,071	Oct. 15, 1996	Demaray et al.	204	192	
		5,603,816	Feb. 18, 1997	Demaray et al.	204	298	
		5,607,789	Mar. 4, 1997	Treger et al.	429	90	
		5,613,995	Mar. 25, 1997	Bhandarkar et al.	65	384	
		5,654,054	Aug. 5, 1997	Tropsha et al.	428	36.6	
		5,654,984	Aug. 5, 1997	Hershbarger et al.	375	257	
		5,693,956	Dec. 2, 1997	Shi et al.	257	40	
		5,718,813	Feb. 17, 1998	Drummond	204	192.2	
		5,719,976	Feb. 17, 1998	Henry et al.	385	50	
		5,792,550	Aug. 11, 1998	Phillips et al.	428	336	
		5,831,262	Nov. 3, 1998	Greywall et al.	250	227	
		5,841,931	Nov. 24, 1998	Foresi et al.	385	131	
		5,847,865	Dec. 8, 1998	Gopinath et al.	359	343	
		5,853,830	Dec. 29, 1998	McCaulley et al.	428	35.7	
		5,855,744	Jan. 5, 1999	Halsey et al.	204	192	
		5,900,057	May. 4, 1999	Buchal et al.	117	109	

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	5,948,215	Sep. 7, 1999	Lantsman	204	192.12	
	5,961,682	Oct. 5, 1999	Lee et al.	65	384	
	5,966,491	Oct. 12, 1999	DiGiovanni	385	127	
	5,977,582	Nov. 2, 1999	Fleming et al.	257	310	
	6,001,224	Dec. 14, 1999	Drummond	204	192.12	
	6,024,844	Feb. 15, 2000	Drummond et al.	204	192.12	
	6,051,114	Apr. 18, 2000	Yao et al.	204	192.3	
	6,051,296	Apr. 18, 2000	McCaulley et al.	428	35.7	
	6,058,233	May 2, 2000	Dragone	385	46	
	6,080,643	Jun. 27, 2000	Noguchi et al.	438	487	
	6,093,944	Jul. 25, 2000	VanDover	257	310	
	6,106,933	Aug. 22, 2000	Nagai et al.	428	212	
	6,146,225	Nov. 14, 2000	Sheats et al.	445	24	
	6,157,765	Dec. 5, 2000	Bruce et al.	385	129	
	6,162,709	Dec. 19, 2000	Raux et al.	438	513	
	6,176,986 B1	Jan. 23, 2001	Watanabe et al.	204	298.13	
	6,248,291 B1	Jun. 19, 2001	Nakagama et al.	419	46	
	6,280,585 B1	Aug. 28, 2001	Obinata et al.	204	298.19	
	6,287,986 B1	Sep. 11, 2001	Mihara	438	763	
	6,290,822 B1	Sep. 18, 2001	Fleming et al.	204	192.22	
	6,302,939 B1	Oct. 16, 2001	Rabin et al.	75	338	

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	6,344,419 B1	Feb. 5, 2002	Forster et al.	438	758	
	6,350,353 B2	Feb. 26, 2002	Gopalraja et al.	204	192.3	
	6,358,810 B1	Mar. 19, 2002	Dornfest et al.	438	396	
	6,409,965 B1	Jun. 25, 2002	Nagate et al.	419	26	
	6,413,382 B1	Jul. 2, 2002	Wang et al.	204	192.12	
	6,416,598 B1	Jul. 9, 2002	Sircar	148	688	
	6,537,428 B1	Mar. 25, 2003	Xiong et al.	204	192.13	
	6,602,338 B2	Aug. 5, 2003	Chen et al.	252	301.4	

FOREIGN PATENT DOCUMENTS

Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
EP 0 510 883 A2	10/28/92	Europe	H 01 S	3/23	
EP 0 820 088 A2	01/21/98	Europe	H 01 J	37/34	
EP 0 867 985 B1	09/01/98	Europe	H 01 S	3/06	
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WO 02/12932 A2	02/14/02	PCT	H 01 S	3/16	

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FOREIGN PATENT DOCUMENTS							
	Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No	
	WO 96/23085 A1	08/01/96	PCT	C 23 C	14/34		
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Applicant Demaray et al.	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
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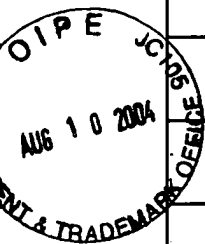


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